PCN Nu	20140410001						F	CN Date:	04/29/2014				
Title:	Assembly/tes	st site	site move from Amkor K1 to TI Taiwan for Select Devices										
Custom	PCN /	Manager		Pho	ne:	+1(214)480-6037 D			Dept: Qu	ept: Quality Services			
Proposed 1 <sup>st</sup> Ship Da		ate:	te: 07/29/20			Estimated Sample Availability:					ovided at request		
Change Type:													
Assembly Site			Design							Wafer Bump Site			
	embly Process embly Materia	Data Sh								np Material np Process			
			<u>ר</u>	<ul> <li>Part number change</li> <li>Test Site</li> </ul>						Wafer Fab			
Mechanical Specification									Wafer Fab				
	3, 11 3,									Wafer Fab	Process		
Descript	PCN Details												
Descript	tion of Chang	je:											
	Assembly/test site move from Amkor K1 to TI Taiwan for Select Devices. Material differences are as follows:									l differences			
			Amkor K1				TI Taiwan						
Mount C	Compound		1013	.361223			4208458						
Mold Co	mpound		1013	319571			4211649						
Lead Fir	nish		Mat	atte Sn			NiPdAu						
Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.													
	Reason for Change:												
							lity. Continuity of		<u> </u>				
	ted impact o	on Fo	rm, Fit	, F	unctio	on,	Quality or Relial	bil	lity	y (positive	/ negative):		
None.													
Changes to product identification resulting from this PCN:													
Sample Product Shipping Label (not actual product label) Assembly Site													
	Amkor K1			Ass	sembly	y Sit	te Origin (22L)			ASO: AM	N		
	TI Taiwan				Assembly Site Origin (22L)					ASO: TA			
INSTRUMENTS       Image: Construction of the second s													

Product Affected:		
ADS5411IPGP	ADS5423IPGP	ADS5424IPGP
ADS5411IPGPR	ADS5423IPGPR	ADS5424IPGPR

Qualification Data:								
This qualification has been specifically developed for the validation of this change. The qualification data								
validates that the proposed change meets the applicable released technical specifications.								
Qual Vehicle : ADS5423IPGP (MSL 3-260C)								
Package Construction Details           Assembly Site:         TI Taiwan         Mold Compound:         4211649								
Assembly Site:	TI Taiv							
# Pins-Designator, Family: 52-PGF		, ,						
Lead Finish, Base     NiPdAu, Cu     Bond Wire:     0.96 Mils Dia., Au       Qualification:     Plan     Test Results								
Sample Size / Fail								
Reliability Test		Conditions		Lot#1	Lot#2	Lot#3		
Manufacturability		(per mfg. Sit	e specification)	Pass	Pass	Pass		
Moisture Sensitivity		(level 3 @ 2		12/0	12/0	12/0		
<b>Reference Qualifica</b>	Reference Qualification Data:							
Qualification Data: 04/17/2014								
This qualification has been developed for the validation of this change. The qualification data								
validates that the proposed change meets the applicable released technical specifications.								
Qual Vehicle 1: 6964BDC0PAPG4 (MSL 3-260C)								
Package Construction Details								
Assembly Site:	TI Tai							
# Pins-Designator, Family:		P, HTQFP	Mount Compound					
Lead Finish, Base	NiPdAu		e: 0.96 Mils Dia., Cu					
Qualification: 🗌 Plan 🛛 Test Results								
Reliability Test		Conditions		•	Size (PAS			
***		1210 (00 )	Lot#1	Lot#2	Lot#3			
**Autoclave 121C **Temperature Cycle		121C (96 H -65/150C (	77/0 77/0	77/0 77/0	77/0 77/0			
Manufacturability (Assemb		-03/1300 (	Pass	-	-			
Moisture Sensitivity	519)	Level 3-26	12/0	12/0	12/0			
**- Preconditioning sequence: Level 3-260C.					12,0	12/0		
Qual Vehicle 2: D610A3BPYP225 (MSL 4-260C)								
Package Construction Details								
Assembly Site:	TI Tai	wan	Mold Compound	d: 4211649				
# Pins-Designator, Family:	208-P	ΥΡ, HTQFP	Mount Compound	: 4208458				
Lead Finish, Base	NiPdAu	ı, Cu	Bond Wir	e: 0.96 I	Ails Dia., A	u		

Qualification:  Plan		est Results						
			Sample Size (PASS/FAIL)					
Reliability Test		Conditions	Lot#1	Lot#2	Lot#3			
**High Temp Storage		170C (420 H	77/0	77/0	77/0			
**Autoclave 121C		121C (96 Hrs	5)	77/0	77/0	77/0		
**Temperature Cycle		-65/150C (50	00 cycles)	77/0	77/0	77/0		
Manufacturability (Assemb	oly)			Pass	-	-		
Moisture Sensitivity		Level 4-260	C	20/0	20/0	20/0		
**- Preconditioning seque	nce: Lev	el 4-260C.						
Qual Vehicle 3: DRV593VFP (MSL 2-260C)								
Package Construction Details								
Assembly Site:	TI Taiw	an	Mold Compound	d: 42116	: 4211649			
# Pins-Designator, Family:	32-VFP,	HLQFP	Mount Compound	d: 42084	: 4208458			
Lead Finish, Base	NiPdAu,	Cu	Bond Wire	e: 0.96 Mils Dia., Cu				
Qualification: 🗌 Plan 🛛 Test Results								
Reliability Test		Conditions	Sample Size (PASS/FAIL)					
		Conditions	Lot#1					
**High Temp Storage		170C (420 H		77/0		77/0		
**Autoclave 121C		121C (96 Hrs	,	77/0				
**Temperature Cycle		-65/150C (50			77/0			
Manufacturability (Assemb	,,		Pass	Pass -				
**- Preconditioning sequence: Level 2-260C.								
Qual Vehicle 4: SLK2511CPZP (MSL 3-260C)								
Package Construction Details								
Assembly Site:	an	4211649						
# Pins-Designator, Family:	100-PZP	P, HTQFP	1: 4208458					
Lead Finish, Base	NiPdAu,		e: 0.96 Mils Dia., Cu					
Qualification: 🗌 Plan 🛛 Test Results								
Reliability Test		Conditions	Sample Size (PASS/F/		S/FAIL)			
•			Lot#1	Lot#2	Lot#3			
**High Temp Storage		170C (420 H	1	77/0	77/0	77/0		
**Autoclave 121C		121C (96 Hrs	, ,	77/0	77/0	77/0		
**Temperature Cycle		-65/150C (50	77/0	77/0	77/0			
Manufacturability (Assemb	oly)		-	Pass	-	-		
Moisture Sensitivity	-	Level 3-260	12/0	12/0	12/0			
**- Preconditioning seque	nce: Lev	el 3-260C.						

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com